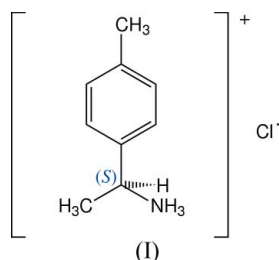


(S)-(-)-1-(4-Methylphenyl)ethylammonium chlorideGuadalupe Hernández,^a Sylvain Bernès,^{b*} Roberto Portillo^a and René Gutiérrez^a^aLaboratorio de Síntesis de Complejos, Facultad de Ciencias Químicas, Universidad Autónoma de Puebla, AP 1067, 72001 Puebla, Pue., Mexico, and ^bDEP Facultad de Ciencias Químicas, UANL, Guerrero y Progreso S/N, Col. Treviño, 64570 Monterrey, NL, MexicoCorrespondence e-mail:
sylvain_bernes@hotmail.com**Key indicators**Single-crystal X-ray study
 $T = 296$ K
Mean $\sigma(\text{C}-\text{C}) = 0.003$ Å
 R factor = 0.043
 wR factor = 0.116
Data-to-parameter ratio = 19.2For details of how these key indicators were automatically derived from the article, see <http://journals.iucr.org/e>.In the chiral title salt, $\text{C}_9\text{H}_{14}\text{N}^+\cdot\text{Cl}^-$, cations and anions are held together by $\text{N}-\text{H}\cdots\text{Cl}$ hydrogen bonds, forming a one-dimensional network in the crystal structure.Received 8 December 2006
Accepted 23 January 2007**Comment**Reactions in dry media or under solvent-free conditions are becoming an area of growing interest; they are especially appealing as they provide rapid reaction rates, clean reaction conditions and ease of manipulation (Tanaka & Toda, 2000; Jeon *et al.*, 2005). As part of an ongoing program to develop benign and expeditious methods for organic transformations under solvent-free conditions, we have undertaken the preparation of chiral amides. The title salt, (I) (Fig. 1), was observed as a by-product in such reactions (see *Experimental*).

The (*p*-tolyl)ethylammonium cation found in (I) has been crystallographically characterized with a number of anions (*e.g.* Bálint *et al.*, 2004); however no halogenide salts have been reported so far. In contrast, the crystal structure of (*R*)-1-phenylethylammonium bromide, (II), has been reported recently (Fischer, 2006); this is based on a layered network formed through $\text{N}-\text{H}\cdots\text{Br}$ hydrogen bonds. Interestingly, the crystal structure of (I) is different from that observed for (*R*)-1-phenylethylammonium bromide, even though both compounds crystallize in the same space group with similar cell parameters. In (I), ammonium H atoms are involved in $\text{N}-\text{H}\cdots\text{Cl}$ hydrogen bonds (Table 1), forming $R(8)$ motifs. Edge-sharing motifs propagate along [100], forming a one-dimensional chain (Fig. 2). Differences in interionic contacts between (I) and (II) are reflected in a limited, but significant modification of the conformation of the cation: the dihedral angle between the benzene ring and $\text{N}_{\text{ammonium}}/\text{C}_{\text{methine}}/\text{C}_{\text{methyl}}$ plane ($\text{N}1/\text{C}1/\text{C}2$) is 66.02 (12°) in (I), *versus* 72.7° in (II).

ExperimentalUnder solvent-free conditions, (*S*)-(-)-1-(4-methylphenyl)ethylamine (0.378 g, 2.8 mmol) and pyridine-2,6-dicarbonyl dichloride (0.286 g, 1.4 mmol) were mixed at 298 K. The resulting crude product

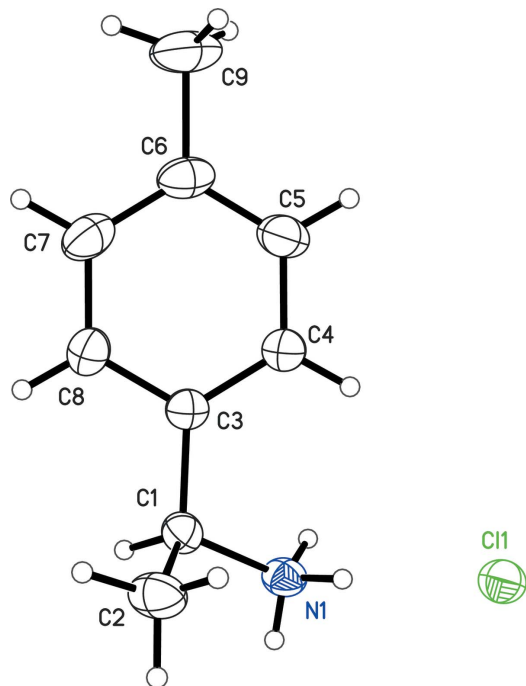


Figure 1
The structure of (I) with displacement ellipsoids drawn at the 30% probability level for non-H atoms.

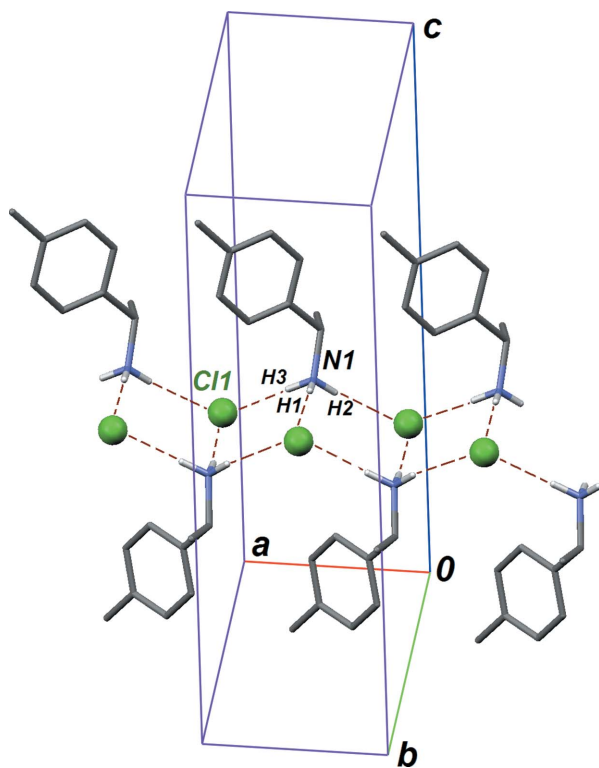


Figure 2
Part of the crystal structure of (I), showing hydrogen bonds as dashed lines. C-bound H atoms have been omitted for clarity.

was recrystallized from ethanol, affording the expected diamide (96% yield) and (I) as a by-product (less than 2% yield).

Crystal data

$C_9H_{14}N^+ \cdot Cl^-$
 $M_r = 171.66$
Orthorhombic, $P2_12_12_1$
 $a = 5.4849$ (9) Å
 $b = 9.1520$ (13) Å
 $c = 19.867$ (4) Å
 $V = 997.3$ (3) Å³

$Z = 4$
 $D_x = 1.143$ Mg m⁻³
Mo $K\alpha$ radiation
 $\mu = 0.33$ mm⁻¹
 $T = 296$ (1) K
Prism, colourless
 $0.60 \times 0.40 \times 0.22$ mm

Data collection

Bruker P4 diffractometer
 $2\theta/\omega$ scans
Absorption correction: ψ scan
(*XSCANS*; Siemens, 1996)
 $T_{min} = 0.767$, $T_{max} = 0.929$
2315 measured reflections
2128 independent reflections

1779 reflections with $I > 2\sigma(I)$
 $R_{int} = 0.039$
 $\theta_{max} = 30.0^\circ$
3 standard reflections
every 97 reflections
intensity decay: 5.3%

Refinement

Refinement on F^2
 $R[F^2 > 2\sigma(F^2)] = 0.043$
 $wR(F^2) = 0.1116$
 $S = 1.03$
2128 reflections
111 parameters
H atoms treated by a mixture of independent and constrained refinement

$w = 1/[\sigma^2(F_o^2) + (0.0642P)^2 + 0.076P]$
where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{max} < 0.001$
 $\Delta\rho_{max} = 0.30$ e Å⁻³
 $\Delta\rho_{min} = -0.24$ e Å⁻³
Absolute structure: Flack (1983),
431 Friedel pairs
Flack parameter: 0.01 (9)

Table 1

Hydrogen-bond geometry (Å, °).

<i>D</i> —H... <i>A</i>	<i>D</i> —H	H... <i>A</i>	<i>D</i> ... <i>A</i>	<i>D</i> —H... <i>A</i>
N1—H1...Cl1 ⁱ	0.90 (3)	2.29 (3)	3.1552 (19)	160 (2)
N1—H2...Cl1 ⁱⁱ	0.82 (4)	2.38 (4)	3.157 (2)	159 (3)
N1—H3...Cl1	0.89 (4)	2.29 (4)	3.180 (2)	179 (3)

Symmetry codes: (i) $x - \frac{1}{2}, -y + \frac{3}{2}, -z + 1$; (ii) $x - 1, y, z$.

H atoms bonded to C atoms were placed in idealized positions and refined with a riding model approximation. Constrained C—H distances: 0.93 for aromatic CH, 0.96 for methyl CH₃ and 0.98 Å for methine CH. Isotropic displacement parameters: $U_{iso}(H) = 1.2U_{eq}(C)$ for aromatic and methine (CH) and $1.5U_{eq}(C)$ for methyl H atoms. Methyl groups were considered as rigid rotating groups. H atoms bound to N1 were found in a difference map and their coordinates refined freely, with $U_{iso}(H) = 1.5U_{eq}(N1)$.

Data collection: *XSCANS* (Siemens, 1996); cell refinement: *XSCANS*; data reduction: *XSCANS*; program(s) used to solve structure: *SHELXTL-Plus* (Sheldrick, 1998); program(s) used to refine structure: *SHELXTL-Plus*; molecular graphics: *SHELXTL-Plus*; software used to prepare material for publication: *SHELXTL-Plus*.

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